

## Supporting Information

### **Monolayers of Diblock Copolymer Micelles by Spin-coating from O-xylene on SiO<sub>x</sub>/Si Studied in Real and Reciprocal Space**

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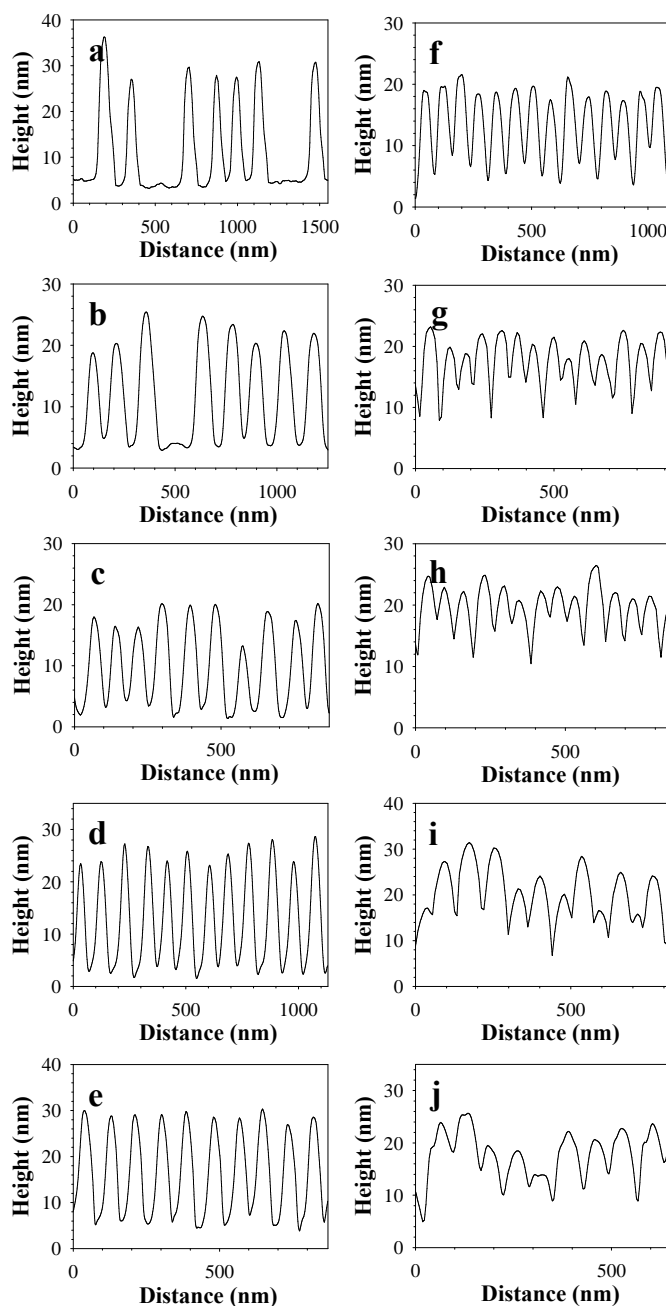


Figure S1 AFM height profiles for micelles on SiO<sub>x</sub>/Si spun from o-xylene solutions containing P(S-*b*-2VP) micelles at mass fractions: (a) 0.1, (b) 0.2, (c) 0.3, (d) 0.4, (e)

0.5, (f) 0.6, (g) 0.7, (h) 0.8, (i) 0.9 and (j) 1.0 mass %.

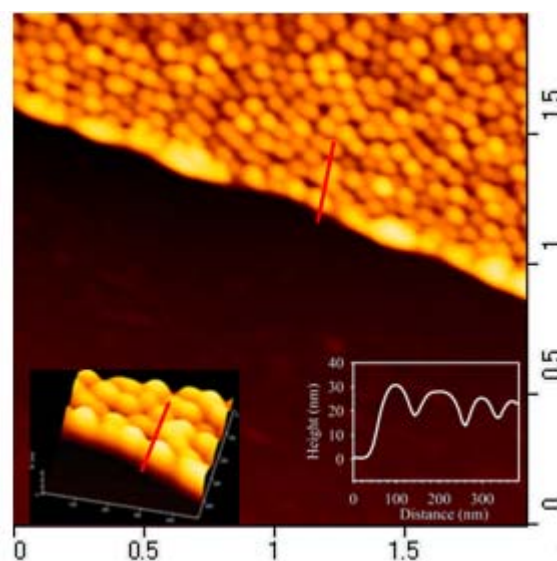


Figure S2 Cross-section AFM image of the surface morphology of a scratched film (initially spin coated from 1 mass% polymer solution). The bottom-left inset reveals a 3-dimensional topography and the bottom-right inset shows a height profile.

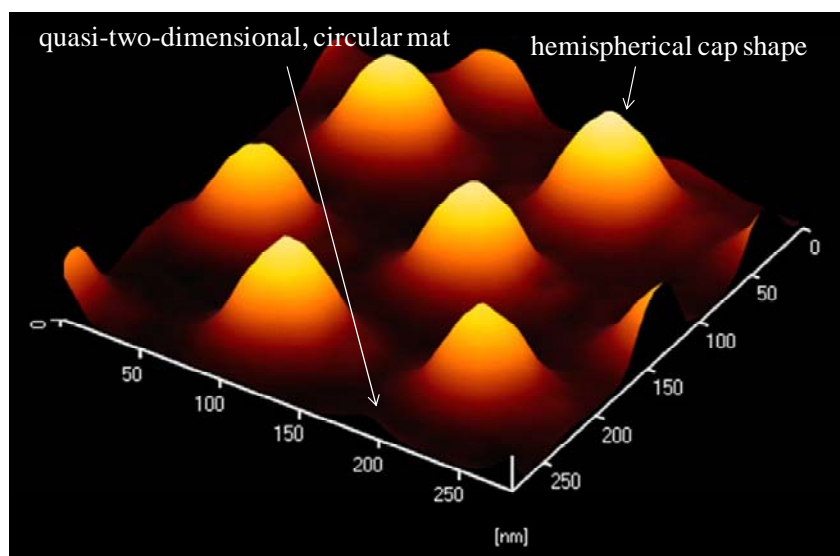


Figure S3 3-dimensional AFM tomography of micelles as-spun from a 0.2 mass % P(S-*b*-2VP) polymer solution.

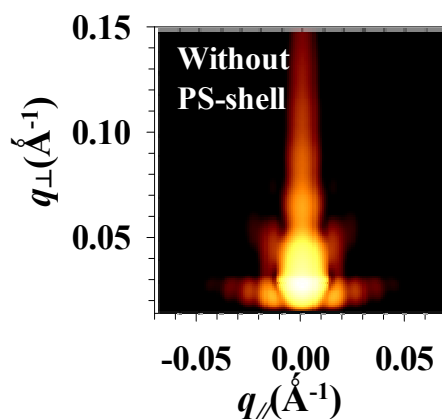


Figure S4 Simulated 2D GISAXS pattern of the form factor of a truncated sphere without PS shell.

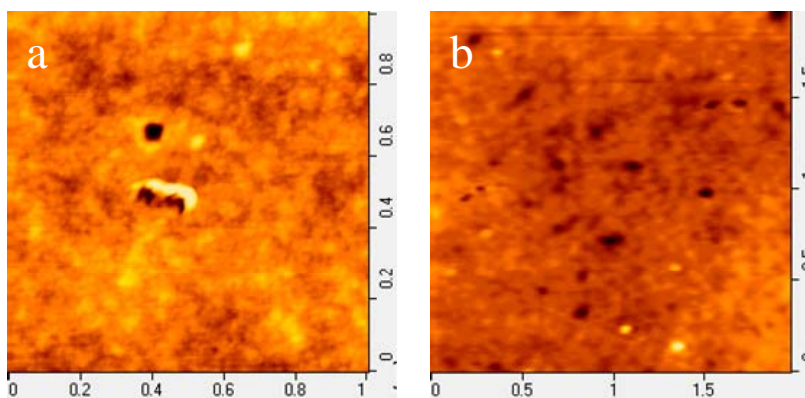


Figure S5 AFM topographies of solvent-annealed thin films in (a) toluene (20 min) and (b) THF (120 min). The sample (a) was prepared by spin coating from a solution of P(S-*b*-2VP) 0.3 mass % in o-xylene whereas the sample (b) was prepared by spin coating from 0.8 mass %